

# N-Channel SuperFET<sup>®</sup> II MOSFET 800 V, 2.6 A, 2.25 $\Omega$

# Features

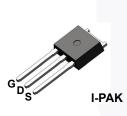
- R<sub>DS(on)</sub> = 1.87 Ω (Typ.)
- Ultra Low Gate Charge (Typ. Q<sub>g</sub> = 11 nC)
- Low E<sub>oss</sub> (Typ. 1.1 uJ @ 400V)
- Low Effective Output Capacitance (Typ. C<sub>oss(eff.)</sub> = 51 pF)
- 100% Avalanche Tested
- RoHS Complian
- ESD Improved Capability

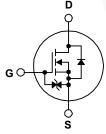
### Applications

- AC DC Power Supply
- LED Lighting

# Description

SuperFET<sup>®</sup> II MOSFET is Fairchild Semiconductor's brand-new high voltage super-junction (SJ) MOSFET family that is utilizing charge balance technology for outstanding low on-resistance and lower gate charge performance. This technology is tailored to minimize conduction loss, provide superior switching performance, dv/dt rate and higher avalanche energy. Consequently, SuperFET II MOSFET is very suitable for the switching power applications such as Audio, Laptop adapter, Linghting, ATX power and industrial power applications.





# Absolute Maximum Ratings T<sub>C</sub> = 25°C unless otherwise noted.

Symbol		FCU2250N80Z	Unit			
V <sub>DSS</sub>	Drain to Source Voltage	800	V			
V <sub>GSS</sub>	Cata ta Causa Maltana	- DC		±20	V	
	Gate to Source Voltage	- AC	- AC (f > 1 Hz)			
I <sub>D</sub>	Drain Current	- Continuous (T <sub>C</sub> = 25 <sup>o</sup> C)	2.6			
		- Continuous ( $T_C = 100^{\circ}C$ )		1.7	A	
I <sub>DM</sub>	Drain Current	- Pulsed	(Note 1)	6.5	Α	
E <sub>AS</sub>	Single Pulsed Avalanche Energy (Note 2)			21.6	mJ	
I <sub>AR</sub>	Avalanche Current	(Note 1)	0.52	Α		
E <sub>AR</sub>	Repetitive Avalanche Energy (Note			0.39	mJ	
dv/dt	MOSFET dv/dt	100	V/ns			
	Peak Diode Recovery dv/dt (Note 3)			20		
P <sub>D</sub>	Devues Dissinction	(T <sub>C</sub> = 25°C)		39	W	
	Power Dissipation	- Derate Above 25°C		0.31	W/ºC	
T <sub>J</sub> , T <sub>STG</sub>	Operating and Storage Temperature Range			-55 to +150	°C	
TL	Maximum Lead Temperature for Soldering, 1/8" from Case for 5 Seconds			300	°C	

### **Thermal Characteristics**

Symbol	Parameter	FCU2250N80Z	Unit	
$R_{ ext{ heta}JC}$	Thermal Resistance, Junction to Case, Max.	3.2	°C/W	
$R_{ ext{ heta}JA}$	Thermal Resistance, Junction to Ambient, Max.	100		

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Part N	Part Number Top Mark Packa		Package	Packing Method	Reel Size	Tape Width		Quantity	
FCU225	FCU2250N80Z FCU225080Z IPAK			Tube	N/A	N/A		75 units	
Electric	al Chai	racteristics ⊤ <sub>c</sub> =	25ºC unless	otherwise noted.				-	
Symbol	Parameter			Test Condi	tions	Min.	Тур.	Max.	Unit
Off Chara	acteristic	s							
BV <sub>DSS</sub>	Drain to Source Breakdown Voltage		oltage	V <sub>GS</sub> = 0 V, I <sub>D</sub> = 1 mA, T <sub>J</sub> = 25°C		800	-	-	V
∆BV <sub>DSS</sub>	Breakdown Voltage Temperature Coefficient		-	$I_D = 1 \text{ mA}, \text{ Referenced to } 25^{\circ}\text{C}$			0.95		V/ºC
$/\Delta T_J$						-	0.85	-	V/°C
I <sub>DSS</sub>	Zero G	Zero Gate Voltage Drain Current		$V_{DS}$ = 800 V, $V_{GS}$ = 0		-	-	25	μA
USS	Zero Gale Vollage Drain Current		,110	$V_{DS}$ = 640 V, $V_{GS}$ = 0 V, $T_{C}$ = 125°C		-	-	250	μΛ
I <sub>GSS</sub>	Gate to	Body Leakage Current	t	$V_{GS} = \pm 20 \text{ V}, \text{ V}_{DS} = 0$	V	-	-	±10	μA
On Chara	cteristic	S							
V <sub>GS(th)</sub>		hreshold Voltage		$V_{GS} = V_{DS}, I_{D} = 0.26$	mA	2.5	-	4.5	V
R <sub>DS(on)</sub>		Drain to Source On Res	istance	$V_{GS} = 10 \text{ V}, \text{ I}_{D} = 1.3 \text{ A}$		-	1.87	2.25	Ω
9FS	Forwar	d Transconductance		$V_{DS} = 20 \text{ V}, \text{ I}_{D} = 1.3 \text{ A}$		-	2.28	-	S
Dynamic	Charact	eristics							
C <sub>iss</sub>	Input Capacitance			100 Y Y 0 Y		-	440	585	pF
C <sub>oss</sub>	Output	tput Capacitance		V <sub>DS</sub> = 100 V, V <sub>GS</sub> = 0 V, f = 1 MHz		-	16	22	pF
C <sub>rss</sub>	Revers	e Transfer Capacitance	;			-	0.75	-	pF
C <sub>oss</sub>	Output	Output Capacitance		V <sub>DS</sub> = 480 V, V <sub>GS</sub> = 0	) V, f = 1 MHz	-	8.4	-	pF
C <sub>oss(eff.)</sub>	Effective Output Capacitance			$V_{DS} = 0 V$ to 480 V, $V_{GS} = 0 V$ $V_{DS} = 640 V$ , $I_D = 2.6 A$ ,		-	51	-	pF
Q <sub>g(tot)</sub>	Total G	Total Gate Charge at 10V V				-	11	14	nC
Q <sub>gs</sub>	Gate to	Source Gate Charge		V <sub>GS</sub> = 10 V (Note 4)		-	2.2	-	nC
Q <sub>gd</sub>	Gate to	Drain "Miller" Charge				-	4.3	-	nC
ESR	Equiva	lent Series Resistance		f = 1 MHz		-	2.8	-	Ω
Switching	g Charac	teristics							
t <sub>d(on)</sub>	Turn-O	n Delay Time				-	11	32	ns
t <sub>r</sub>	Turn-O	n Rise Time		$V_{DD} = 400 \text{ V}, \text{ I}_{D} = 2.6 \text{ A},$ $V_{GS} = 10 \text{ V}, \text{ R}_{g} = 4.7 \Omega$ (Note 4)		-	6.7	23	ns
t <sub>d(off)</sub>	Turn-O	ff Delay Time					26	62	ns
t <sub>f</sub>	Turn-O	ff Fall Time				-	8.7	27	ns
	urce Dio	de Characteristic	s			7			_
I <sub>S</sub>	Maximum Continuous Drain to Source Diode Forw			e Forward Current		-	-	2.6	А
I <sub>SM</sub>	Maximum Pulsed Drain to Source Diode Fo					-	-	6.5	A
V <sub>SD</sub>	Drain to Source Diode Forward Voltage			$V_{GS} = 0 V, I_{SD} = 2.6 A$		-	_	1.2	V
t <sub>rr</sub>		e Recovery Time	30	$V_{GS} = 0 V, I_{SD} = 2.6 A,$ $V_{GS} = 0 V, I_{SD} = 2.6 A,$		-	260	-	ns
Q <sub>rr</sub>	Reverse Recovery Charge			$dI_{\rm F}/dt = 100  {\rm A}/{\mu {\rm s}}$		_	2.2		μC

 $\begin{aligned} &2.\ I_{AS} = 0.52\ A,\ R_G = 25\ \Omega,\ starting\ T_J = 25^\circ C. \\ &3.\ I_{SD} \leq 2.6\ A,\ di/dt \leq 200\ A/\mu s,\ V_{DD} \leq BV_{DSS},\ starting\ T_J = 25^\circ C. \end{aligned}$ 

Essentially independent of operating temperature typical characteristics.

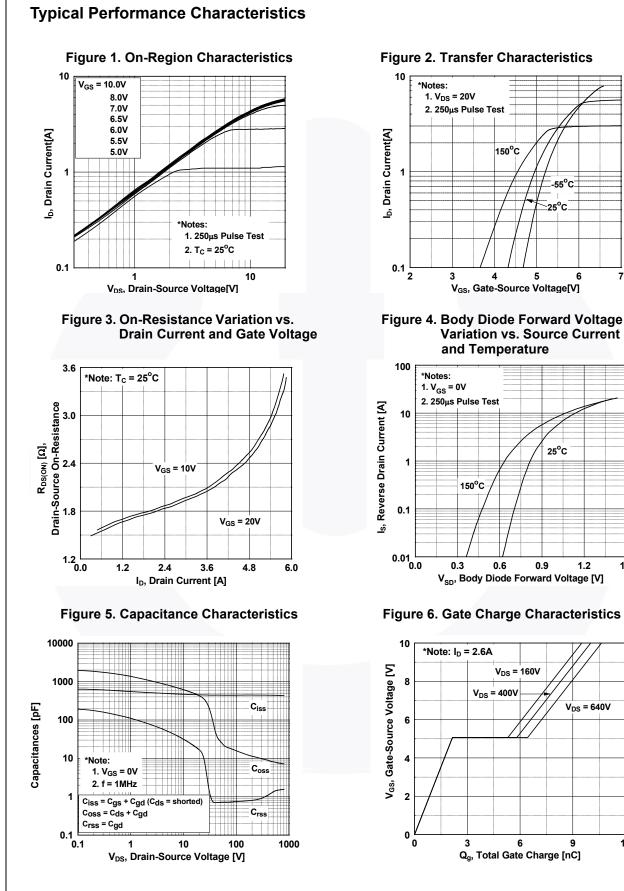


Figure 2. Transfer Characteristics

150°C

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-55°C 25°C

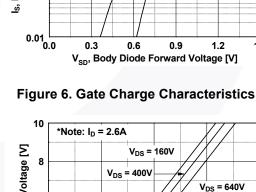
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7

1.5

5

25°C



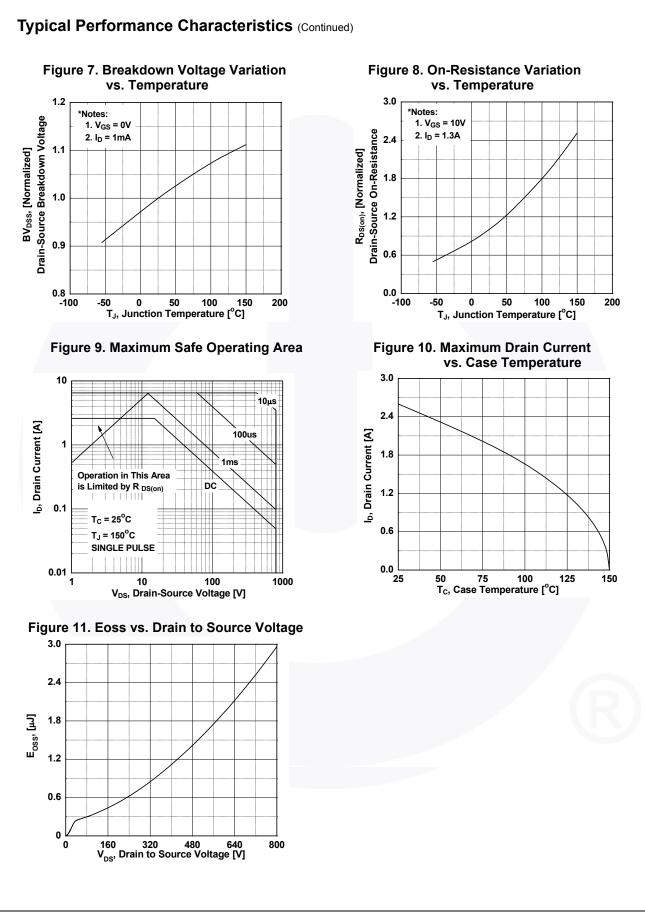
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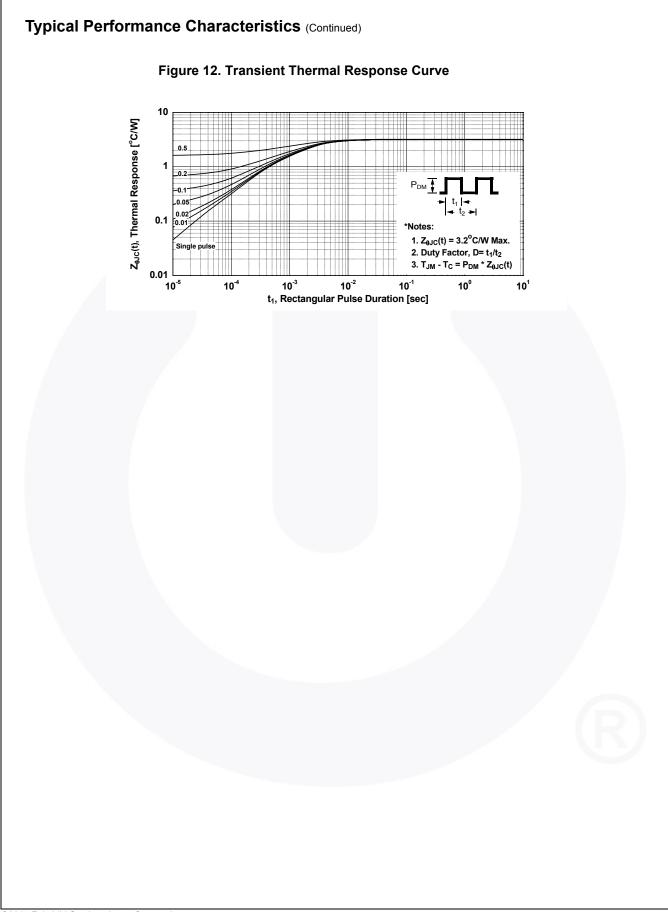
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FCU2250N80Z — N-Channel SuperFET<sup>®</sup> II MOSFET

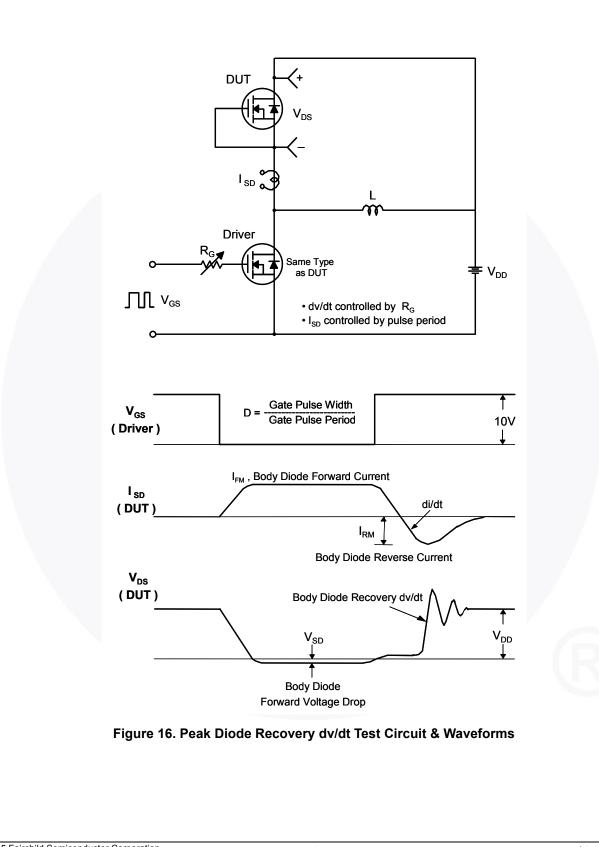


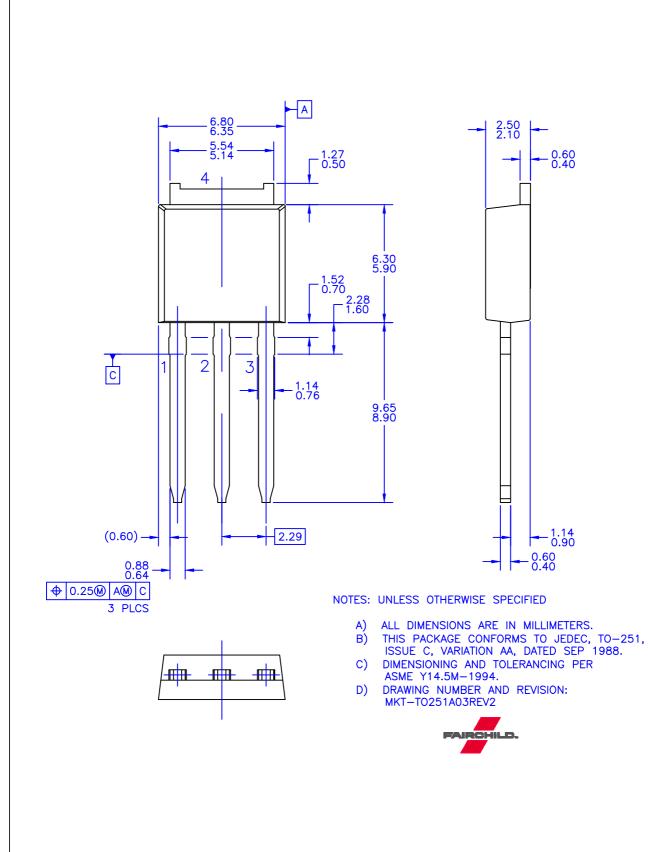


 $V_{GS}$ ק∠ Qg 10V ≑v∝ V<sub>GS</sub>  $\mathsf{Q}_{\mathrm{gd}}$ a Η DUT 1mA Charge Figure 13. Gate Charge Test Circuit & Waveform  $\mathsf{R}_{\mathsf{L}}$ V<sub>DS</sub> V<sub>DS</sub>) 90% VDD Ycs R<sub>G</sub> 10 % V<sub>GS</sub> DUT 10V Л Figure 14. Resistive Switching Test Circuit & Waveforms L  $E_{AS} = -\frac{1}{2} L I_{AS}^2$ Vos BV<sub>DSS</sub> п I<sub>AS</sub> Rg ÷∨տ  $I_{D}(t)$ VDD DUT 10V V<sub>DS</sub> (t) Time Figure 15. Unclamped Inductive Switching Test Circuit & Waveforms

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